Application/Control No. Applicant(s)/Patent Under Reexamination 10/035,690 CHEN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 DAVID VU 2818 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY * US-6,103,456 08-2000 Tobben et al. 430/317 430/316 03-2000 US-6,042,999 Lin et al. В * 438/637 06-2001 Harada et al. US-6,251,774 С US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-FOREIGN PATENT DOCUMENTS Document Number Country Code-Number-Kind Code Date Country Name Classification MM-YYYY Ν 0 Ρ Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

W